Examinator-Pro

Files

Galaxy Database

Yield-Man Lite supercharges Examinator-Pro by connecting it to the same MariaDB database used by Yield-Man (enterprise yield management system). This power enables long term trend analysis, correlations across multiple test flows (temperatures, fab, wafer sort, final test, etc.) and fast report generation even for huge datasets. The database also facilitates deep, multi-variable characterization reducing, as one customer shared, the total characterization time from 6 months to only 6 hours!

Databases can be created for Production or Engineering data and they can be located on centralized servers, or on users' laptops giving the utmost flexibility.

The relational database aligns data from the fab with corresponding wafer probe and even downstream to final test, correlating problems back to the fab using genealogy reports, and creates wafermaps of final test data highlighting possible geographical sensitivities.

Even with all this power, Galaxy's software is intuitive, easy to use, and requires no special training. Because Examinator-Pro acts as a common user interface for all Galaxy products, growing into Yield-Man Lite is transparent for users. It's the perfect bridge between file-based analysis using Examinator-Pro and Galaxy's fully automated enterprise yield management system (Yield-Man).

For more than 25 years Galaxy Semiconductor has been and continues to be the trusted solution for enhancing yields, reducing defects per million (DPM), and optimizing semiconductor manufacturing processes. Galaxy's experienced team provides powerful, scalable, and easy to use intelligent data analytics while providing first class support.

FEATURES AND BENEFITS

- **TEST DATA VALIDATION & INSERTION:** Manually insert test data into the Galaxy database, it's then validated against user-defined criteria

- **DATA INGESTION:** Processes all popular test data formats, including STDF, GDF, WAT, PCM, compressed files and over 120 more formats

- **ACCURATE & CONSOLIDAION OF TEST RE-TEST DATA:** Automatically consolidates test and retest data to provide an accurate yield assessment

- **DIE TRACE:** Correlates final test issues to geographical and wafer-specific issues. Interactive drill-down from final test data to exact (x,y) die locations

- **FAB CORRELATION GENEALOGY REPORTS:** Correlates probe test yield with fab parameters, providing lot traceability across the supply chain

- **INTERACTIVE DRILL-DOWN DATA ANALYSIS:** With Examinator-Pro's™ interactive mode, zoom into histograms, trends, scatter plots and wafer maps to examine and compare specific tests for in-depth root cause analysis

- **DEEP MULTI-VARIABLE CHARACTERIZATION:** Reduces total characterization time from 6 months to 6 hours! Flexible, custom variable naming and hierarchy setting allowing for customized reports

- **REPORT CENTER HIGH LEVEL YIELD REPORTS:** View yield trends over time, or split by product, subcon, loadboard, operator, etc.

- **PRODUCTION OR ENGINEERING DATABASES:** Create multiple databases for engineering & production data on users' laptops or centralized servers

- **FAST ANALYSIS FOR LARGE DATASETS:** Query only the parameters you need and / or sample data for even faster query times.

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